

Notice of References Cited	Application/Control No. 10/614,040	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Cynthia Britt	Art Unit 2138	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,968,485	11-2005	Van Kirk, Steve	714/724
*	B	US-4,087,855	05-1978	Bennett et al.	710/100
*	C	US-6,998,892	02-2006	Nguyen et al.	327/161
*	D	US-5,598,035	01-1997	Rusu et al.	257/723
*	E	US-4,090,236	05-1978	Bennett et al.	711/211
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Validation And Test Issues Related to Noise Induced by Parasitic Inductances of VLSI Interconnects" by Sinha et al. IEEE Transactions on Advanced Packaging Publication Date: Aug. 2002 Volume: 25 Issue: 3 pages 329 – 339, INSPEC Accession Number:7496558
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.